

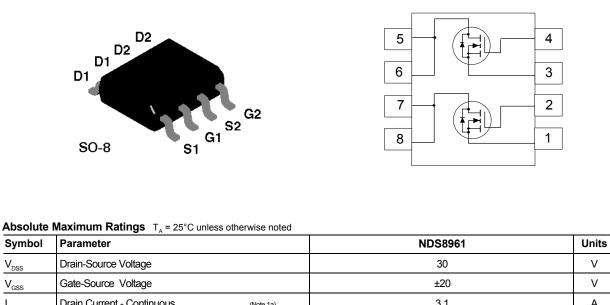
NDS8961 Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- 3.1 A, 30 V. $R_{DS(ON)} = 0.1 \Omega @ V_{GS} = 10 V R_{DS(ON)} = 0.15 \Omega @ V_{GS} = 4.5 V.$
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.

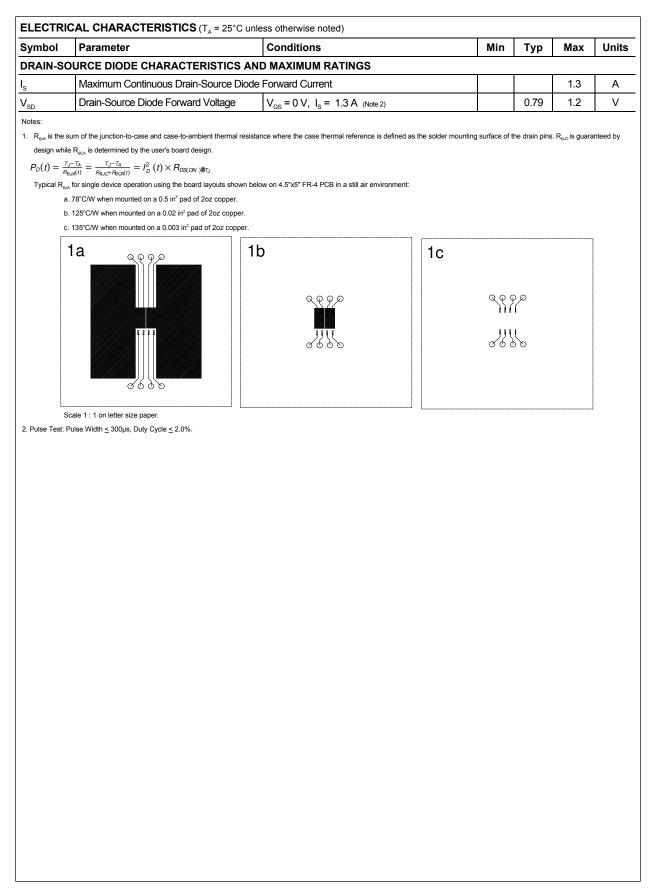


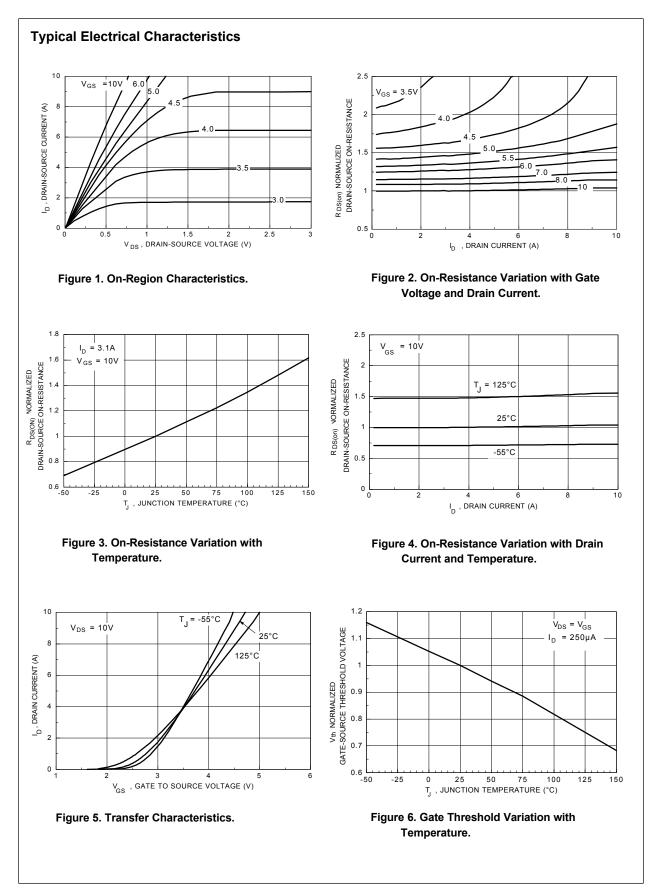
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	3.1	А
	- Pulsed		10	
P _D	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	AL CHARACTERISTICS			
R _{eja}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _{euc}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

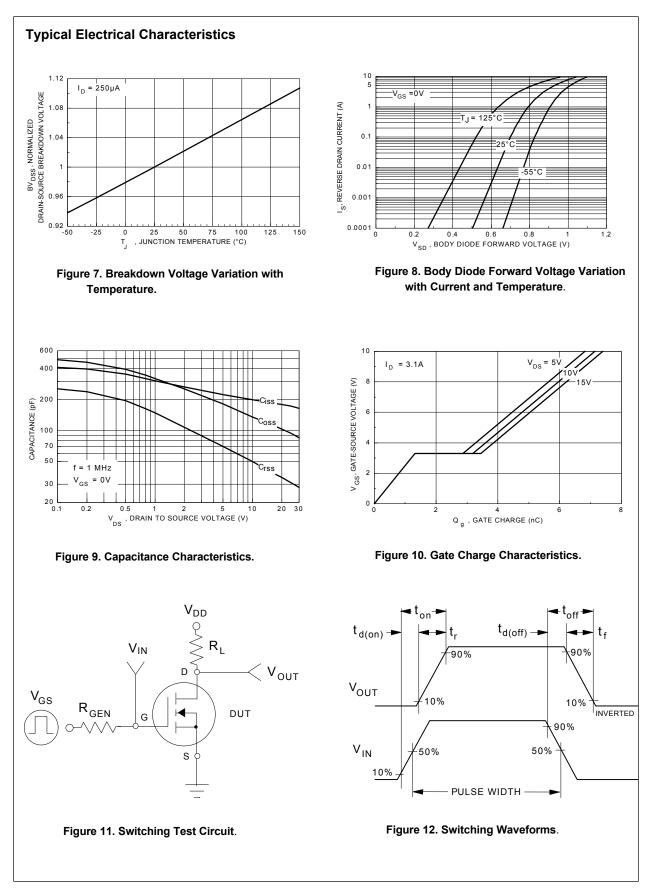
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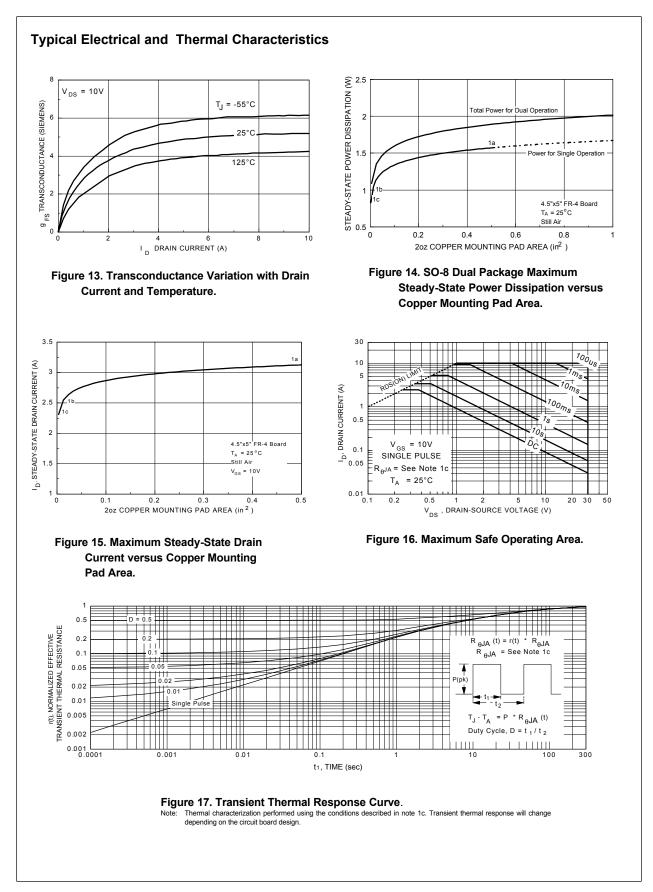
June 1997

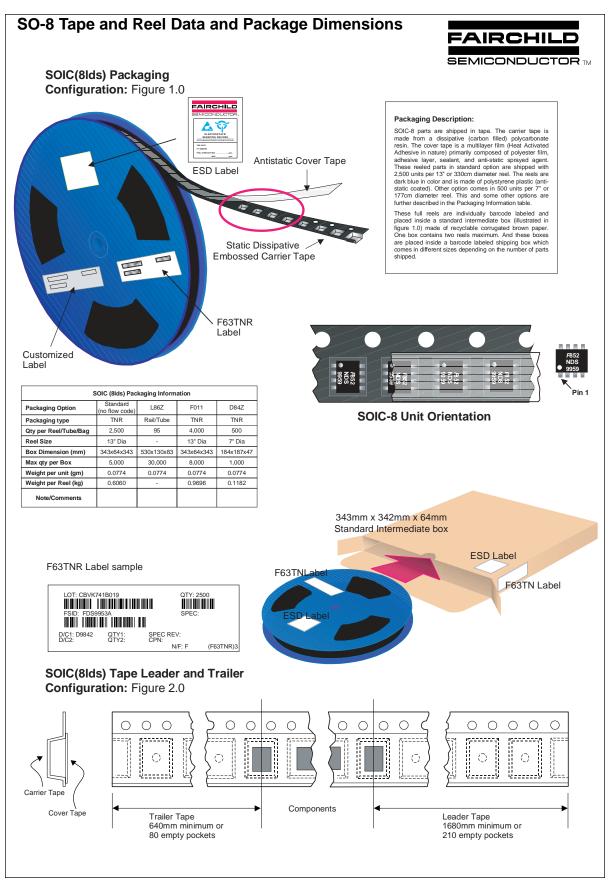
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	$V_{GS} = 0 V, I_{D} = 250 \mu A$				V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V				1	μA
			T _J = 55°C			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						•
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.6	3	V
			T _J = 125°C	0.7	1.2	2	Ī
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 3.1 \text{ A}$			0.072	0.1	Ω
			T _J = 125°C		0.107	0.18]
		$V_{GS} = 4.5 \text{ V}, \ \text{I}_{D} = 2.6 \text{ A}$			0.116	0.15	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 V, V_{DS} = 5 V$		10			Α
		V_{GS} = 4.5 V, V_{DS} = 5 V		4			
9 _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 3.1 \text{ A}$			4.3		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 15 V, V_{CS} = 0 V,$ f = 1.0 MHz			190		pF
C _{oss}	Output Capacitance				120		pF
C _{rss}	Reverse Transfer Capacitance				40		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)			1	1		
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			7	15	ns
ţ,	Turn - On Rise Time				15	30	ns
t _{D(off)}	Turn - Off Delay Time				14	28	ns
t _r	Turn - Off Fall Time				3	6	ns
Q _g	Total Gate Charge	$V_{\rm DS} = 10 V,$			7.1	10	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D} = 3.1 \text{A}, V_{\rm GS} = 10 \text{V}$			1.2		nC
Q_{gd}	Gate-Drain Charge				1.9		nC



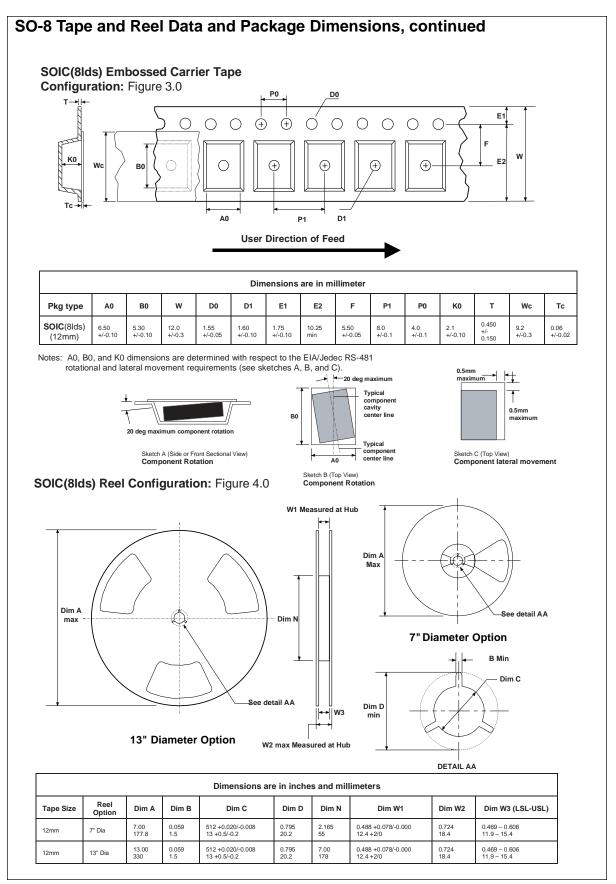


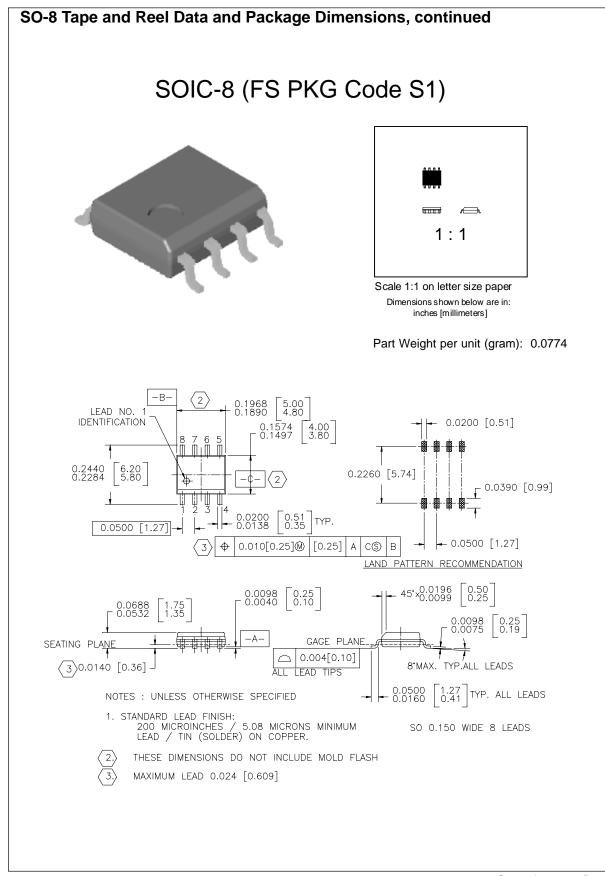






July 1999, Rev. B





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September 1998, Rev. A

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